

**Studies in semiconductor electronics :
DEVELOPMENT OF COMPUTER CONTROLLED
DEEP LEVEL TRANSIENT SPECTROSCOPY (DLTS) SYSTEM
AND TRANSIENT CAPACITANCE STUDIES OF
SOME DEEP IMPURITIES IN SILICON**

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in partial fulfilment for the award of the degree of
DOCTOR OF PHILOSOPHY IN PHYSICS

By
S. V. PANDU RANGAIAH

**DEPARTMENT OF PHYSICS
SRI VENKATESWARA UNIVERSITY
TIRUPATI - 517 502, INDIA.**

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